## Appendix C Summary of Commercial Reliability Programs

National Semiconductor

## **P+ Product Enhancement**

The P+ product enhancement program involves dynamic tests that screen out assembly related and silicon defects that can lead to infant mortality and/or reduce the surviva-

bility of the device under high stress conditions. This program includes but is not limited to the following power devices:

Package Types							
Device	TO-3 K STEEL	TO-39 (H)	TO-220 (T)	DIP (N)	SO (M)	TO-263 (S)	35
LM12	Х					and converse	062
LM109/309	х.	X				·	
LM117/317	х	X	х			х	
LM117HV/317HV	· · · · · X · · · · ·	X		incient	eres.		
LM120/320	X	X	X	4.4.1.1.1		in a second a second	
LM123/323	Х						
LM133/333	X		Х			1.1923 1.124 B	
LM137/337	Х	Х	X				
LM137HV/337HV	Х	Х			e se se e e		08
LM138/338	Х		Х				
LM140/340	Х	Autoria	Х				
LM145/345	X						
LM150/350	х		X		erreis.	··········	
LM195/395	X	X	X				
LM2930/2935/2984			X			Х	Second Second
LM2937			X	an i dana		X	Second Constants
LM2940/2941	a compression pre-		Х			Х	***********
LM2990/2991		********	Х		*****	Х	16
LM2575/2575HV			Х	Х	Х	Х	1104
LM2576			Х		*****	Х	
LM2577			Х	Х	Х	Х	G02
LMD18200/18201			X				
							IC948 IHC86 ILS138 1200